

<b>Notice of References Cited</b>	Application/Control No. 09/965,030	Applicant(s)/Patent Under Reexamination NIWA ET AL.	
	Examiner Kyung H. Shin	Art Unit 2143	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,131,169 A	10-2000	Okazawa et al.	714/7
	B	US-6,370,369 B1	04-2002	Kraiem et al.	455/277.1
	C	US-6,625,745 B1	09-2003	Johnson et al.	714/4
	D	US-6,822,946	11-2004	Wallace, Robert	370/328
	E	US-6,449,647	09-2002	Colby et al.	709/226
	F	US-6,693,915 B1	02-2004	Lappetelainen et al.	370/468
	G	US-6,725,285 B2	04-2004	Van De Meulenhof et al.	710/8
	H	US-6,728,244	04-2004	Takabatake, Yoshiaki	370/392
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.